

<b>Notice of References Cited</b>	Application/Control No. 10/787,133		Applicant(s)/Patent Under Reexamination KAJIYAMA, TAKESHI	
	Examiner Evan Pert		Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,436,770 B1	08-2002	Leung et al.	438/268
*	C	US-5,475,240 A	12-1995	Sakamoto, Osamu	257/67
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	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kedzierski et al., "Design analysis of thin-body silicide source/drain devices, 2001 IEEE International SOI conference, pages 21-22.
	V	Inoh et al., "FBC (Floating Body Cell) for Embedded DRAM on SOI, 2003 Symposium on VLSI Technology Digest of technical Papers, pages 63-64.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.